

CORRIGENDUM:5

Date: 05/03/2026

Tender ID: 2026_IITK_894526_1**Tender Title:** Supply, Installation, and Commissioning of Electron Microscope (Dual Beam FIB-SEM System with Accessories)**Tender Ref. No.:** PI/ACMS/RD/2025-26/NPG/NC-10

Following modifications have been made under technical specification at page no. 29 and 30 to the tender document for the purpose of the Supply, Installation, and Commissioning of the Electron Microscope (Dual Beam FIB-SEM System with Accessories):

1: Main equipment: Dual Beam FIB-SEM

Sl. No.	Description	Specification	
		Original	Modified
1.1.4	System requirements	The offered FIB-SEM system shall support correlative analysis with an existing X-ray based non-destructive inspection system (XRM / Micro-CT)	The offered FIB-SEM system shall enable correlative analysis with existing X-ray based non-destructive inspection systems (e.g., XRM or** Micro-CT) via import of standard volumetric data formats (such as TIFF stack, DICOM, RAW, or equivalent), support for coordinate-based registration, and stage positioning accuracy sufficient for targeted region-of-interest (ROI) navigation. Vendors must specify the stage positioning accuracy and repeatability achievable during such correlative workflows.
1.2.1	Electron Gun	Thermal Schottky type field emission system with crossover-free beam path.	Thermal Schottky type field emission system with current stability. The source should have current stability of 0.25% of beam current for 12 hours under normal operating conditions. Vendors quoting a Thermal Schottky field emission source must provide documented specifications demonstrating that the offered system meets or exceeds all specified probe size, spatial resolution, and beam current stability requirements. Compliance with these specifications must be demonstrated through manufacturer documentation.
1.5.2	Magnification	Ion Column: 300X to 5,00,000X	Ion Column: 500X to 5,00,000X. The system must provide reliable imaging and navigation capability across the full magnification range.

			<p>In particular, the lowest magnification setting shall enable clear large-area navigation suitable for identifying and targeting regions of interest during FIB milling workflows</p> <p>Vendors must provide manufacturer-specified magnification limits and suitably provide documentation or supporting material to demonstrate the above functionality.</p>
1.12.5	Imaging Detectors	Color CCD Camera – 2 nos.	Color CCD/IRCCD/Navigation camera – 2 No's

Terms and conditions: under terms and conditions at page no. 38 following points are added

General terms and conditions	<ol style="list-style-type: none"> 1) The vendor must clearly indicate compliance with each technical specification in a point-by-point compliance statement and also reference the information with the manufacturer's official brochure or datasheet or provide any other supporting material proof from the manufacturer. 2) Systems offering lower specifications than those requested shall not be considered technically compliant, unless the specification explicitly allows equivalence or higher performance.
------------------------------	---

All bidders are requested to consider the above-mentioned incorporated modifications made in the specifications in the technical bid and quote accordingly and provide a separate price bifurcation for the optional accessories, if any. Thank You

N. P. Gurao

Dr. Nilesh Prakash Gurao
 Indenter, EM (DB-FIBSEM)
 ACMS, IITK